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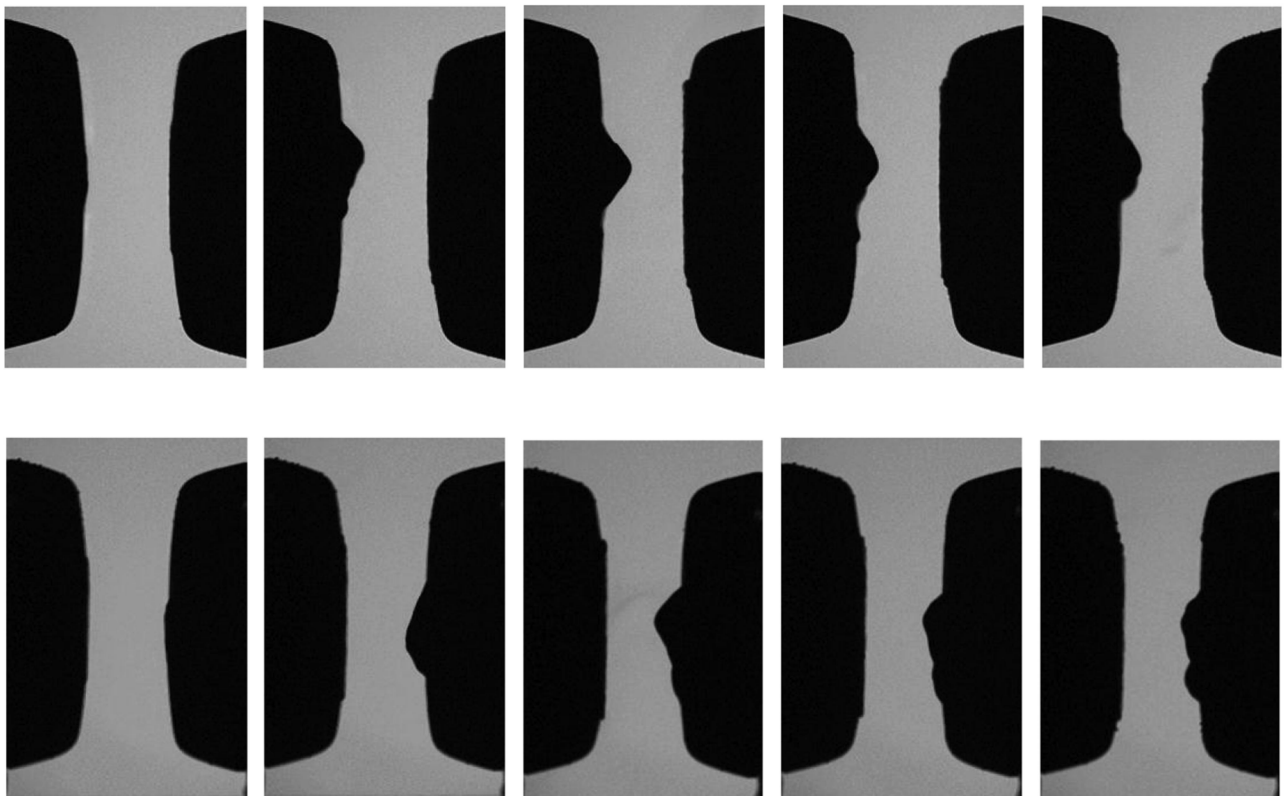
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Cover art from: "The Preceding Voltage Pulse and Separation Welding Mechanism of Electrical Contacts," by XiaoCheng Yang, Jiang Huang, ZhenBiao Li, JinYou Liu, Qian Wang, and Makoto Hasegawa (p. 846–853, Fig. 10).



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